

Dual Symmetric N-Channel 40 V (D-S) MOSFET

PRODUCT SUMMARY

	V _{DS} (V)	R _{DS(on)} (mΩ)(Typ.)	I _D (A) ^a	Q _g (Typ.)
Channel 1	40	7.2 at V _{GS} = 10 V	40	28
		11 at V _{GS} = - 4.5 V	25	
Channel 2	40	5.5 at V _{GS} = 10 V	65	13
		8.9 at V _{GS} = 4.5 V	30	

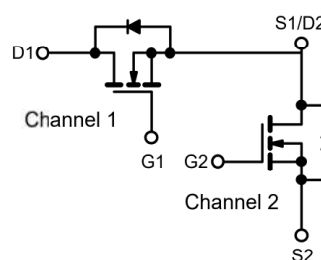
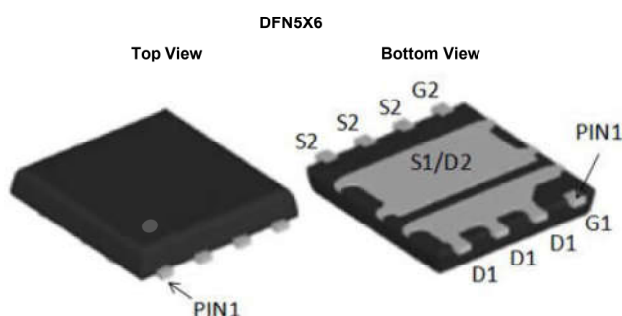
FEATURES

- DT-Trench Power MOSFET
- 100 % R_g and UIS Tested


RoHS
 COMPLIANT

APPLICATIONS

- DC/DC Converters
- On board power for server



Dual N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS T_A = 25 °C, unless otherwise noted

Parameter	Symbol	Channel 1	Channel 2	Unit
Drain-Source Voltage	V _{DS}	40	40	V
Gate-Source Voltage	V _{GS}	± 20	± 20	
Continuous Drain Current (T _J = 150 °C)	I _D	40	65	A
		25	50	
		12 ^{b, c}	27 ^{b, c}	
		10 ^{b, c}	20 ^{b, c}	
Pulsed Drain Current (10 μs Pulse Width)	I _{DM}	160	240	
Source-Drain Current Diode Current	I _S	40	65	
		12 ^{b, c}	19 ^{b, c}	
Pulsed Source-Drain Current	I _{SM}	160	240	
Single Pulse Avalanche Current	L = 0.1 mH I _{AS}	39	63	mJ
Single Pulse Avalanche Energy	E _{AS}	50	156	
Maximum Power Dissipation	P _D	35	50	W
		13	22	
		2.1 ^{b, c}	3.5 ^{b, c}	
		1.28 ^{b, c}	1.89 ^{b, c}	
Operating Junction and Storage Temperature Range	T _J , T _{stg}	- 55 to 150		°C

THERMAL RESISTANCE RATINGS

Parameter		Symbol	Channel 1		Channel 2		Unit
			Typ.	Max.	Typ.	Max.	
Maximum Junction-to-Ambient ^b	t ≤ 10 s	R _{thJA}	30	50	25	40	°C/W
Maximum Junction-to-Case	Steady State	R _{thJC}	3.0	4.0	2	2.5	

Notes:

 a. Based on T_C = 25 °C.

b. Surface Mounted on 1" x 1" FR4 board.

c. t = 10 s.

SPECIFICATIONS T _J = 25 °C, unless otherwise noted							
Parameter	Symbol	Test Conditions		Min.	Typ. ^a	Max.	Unit
Static							
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} = 0 V, I _D = 250 μA	Ch1	40			V
		V _{GS} = 0 V, I _D = 250 μA	Ch2	40			
V _{DS} Temperature Coefficient	ΔV _{DS} /T _J	I _D = 250 μA	Ch1		40		mV/°C
		I _D = 250 μA	Ch2		40		
V _{GS(th)} Temperature Coefficient	ΔV _{GS(th)} /T _J	I _D = 250 μA	Ch1		- 4.5		
		I _D = 250 μA	Ch2		- 4.5		
Gate Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = 250 μA	Ch1	1		3	V
		V _{DS} = V _{GS} , I _D = 250 μA	Ch2	1		3	
Gate-Body Leakage	I _{GSS}	V _{DS} = 0 V, V _{GS} = ± 20 V	Ch1			± 100	nA
		V _{DS} = 0 V, V _{GS} = ± 20 V	Ch2			± 100	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 40 V, V _{GS} = 0 V	Ch1			1	μA
		V _{DS} = 40 V, V _{GS} = 0 V	Ch2			1	
		V _{DS} = 40 V, V _{GS} = 0 V, T _J = 55 °C	Ch1			10	
		V _{DS} = 40 V, V _{GS} = 0 V, T _J = 55 °C	Ch2			10	
On-State Drain Current ^b	I _{D(on)}	V _{DS} = 5 V, V _{GS} = 10 V	Ch1	40			A
		V _{DS} = 5 V, V _{GS} = 10 V	Ch2	65			
Drain-Source On-State Resistance ^b	R _{DS(on)}	V _{GS} = 10 V, I _D = 20 A	Ch1		7.2	8.8	mΩ
		V _{GS} = 10 V, I _D = 30 A	Ch2		5.5	6.5	
		V _{GS} = 4.5 V, I _D = 15 A	Ch1		11	13.5	
		V _{GS} = 4.5 V, I _D = 30 A	Ch2		8.9	10.5	
Forward Transconductance ^b	g _{fs}	V _{DS} = 5 V, I _D = 20 A	Ch1		50		S
		V _{DS} = 5 V, I _D = 30 A	Ch2		65		
Dynamic ^a							
Input Capacitance	C _{iss}	V _{DS} = 20 V, V _{GS} = 0 V, f = 1 MHz	Ch1		728		pF
			Ch2		1550		
Output Capacitance	C _{oss}		Ch1		120		
			Ch2		240		
Reverse Transfer Capacitance	C _{rss}		Ch1		48		
			Ch2		102		
Total Gate Charge	Q _g	V _{DS} = 20 V, V _{GS} = 10 V, I _D = 20 A	Ch1		28		nC
			Ch2		13		
Gate-Source Charge	Q _{gs}		Ch1		2.6		
			Ch2		5.6		
Gate-Drain Charge	Q _{gd}		Ch1		2.6		
			Ch2		9.8		
Gate Resistance	R _g	f = 1 MHz	Ch1		1.5		Ω
			Ch2		3.4		

SPECIFICATIONS $T_J = 25\text{ }^{\circ}\text{C}$, unless otherwise noted							
Parameter	Symbol	Test Conditions	Min.	Typ. ^a	Max.	Unit	
Dynamic ^a							
Turn-On Delay Time	$t_{d(\text{on})}$	$V_{DD} = 20\text{ V}$, $R_L = 2\text{ }\Omega$ $I_D \simeq 20\text{ A}$, $V_{GEN} = 10\text{ V}$, $R_g = 1\text{ }\Omega$	Ch1		7	ns	
			Ch2		9		
Rise Time	t_r		Ch1		10		
			Ch2		19		
Turn-Off Delay Time	$t_{d(\text{off})}$		Ch1		18		
			Ch2		50		
Fall Time	t_f		Ch1		9		
			Ch2		14		
Drain-Source Body Diode Characteristics							
Continuous Source-Drain Diode Current	I_S	$T_C = 25\text{ }^{\circ}\text{C}$	Ch1			40	A
			Ch2			65	
Pulse Diode Forward Current ^a	I_{SM}		Ch1			160	
			Ch2			240	
Body Diode Voltage	V_{SD}	$I_S = 1\text{ A}$	Ch1		0.65	1	V
			Ch2		0.65	1	
Body Diode Reverse Recovery Time	t_{rr}	$I_F = 20\text{ A}$, $di/dt = 100\text{ A}/\mu\text{s}$, $T_J = 25\text{ }^{\circ}\text{C}$	Ch1		17		ns
			Ch2		30		
Body Diode Reverse Recovery Charge	Q_{rr}		Ch1		10		nC
			Ch2		26		
Reverse Recovery Fall Time	t_a		Ch1		10		ns
			Ch2		15		
Reverse Recovery Rise Time	t_b		Ch1		7		
			Ch2		15		

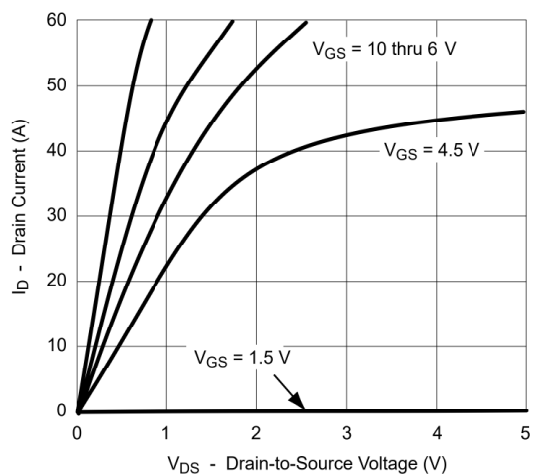
Notes:

a. Guaranteed by design, not subject to production testing.

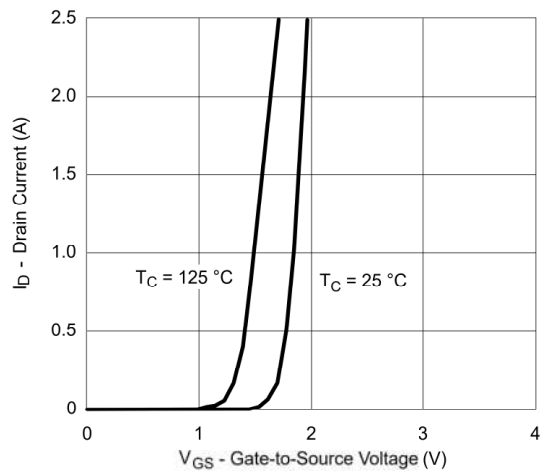
b. Pulse test; pulse width $\leq 300\text{ }\mu\text{s}$, duty cycle $\leq 2\text{ }\%$.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

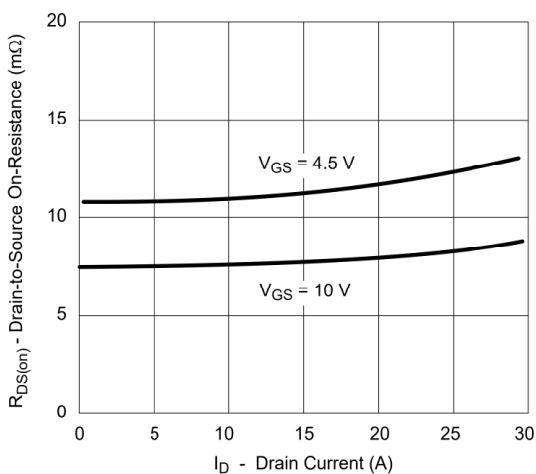
CHANNEL 1 TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



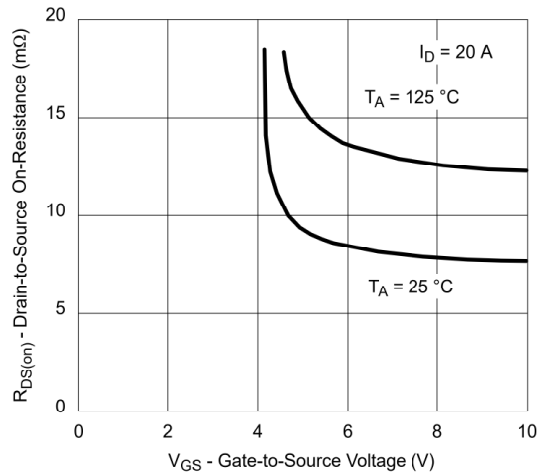
Output Characteristics



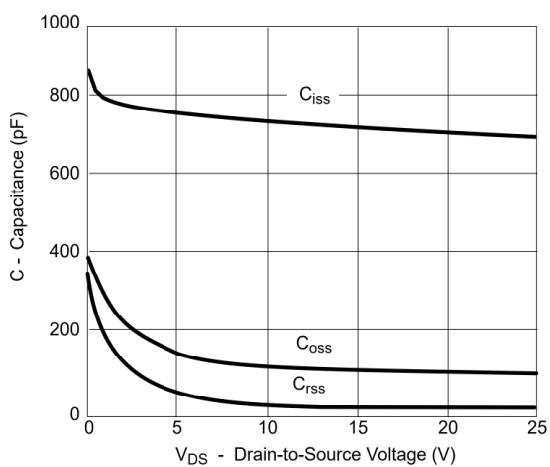
Transfer Characteristics



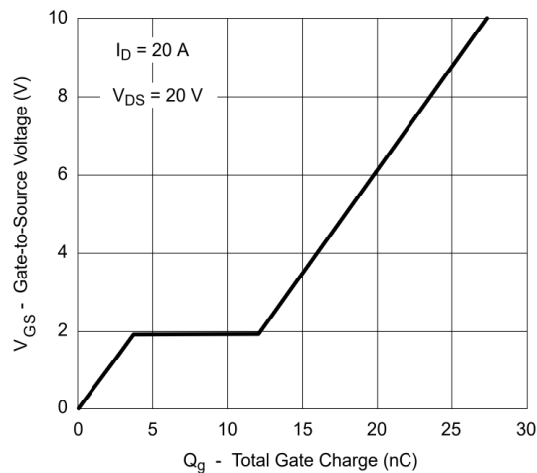
$R_{DS(on)}$ vs. Drain Current



$R_{DS(on)}$ vs. V_{GS} vs. Temperature

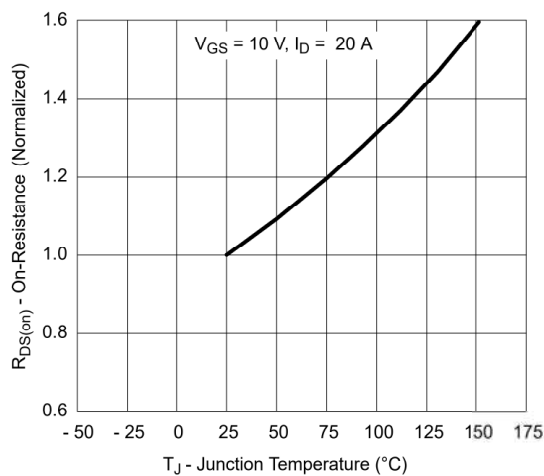


Capacitance

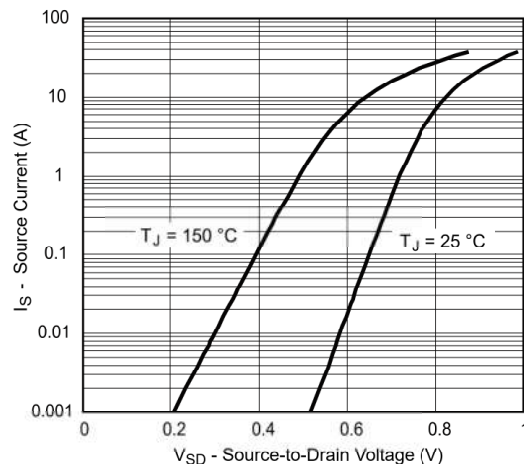


Gate Charge

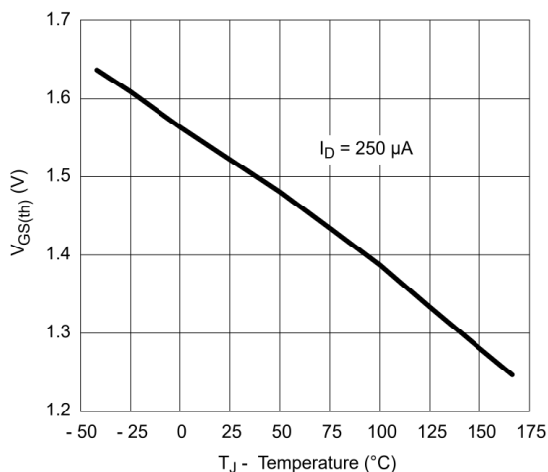
CHANNEL 1 TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



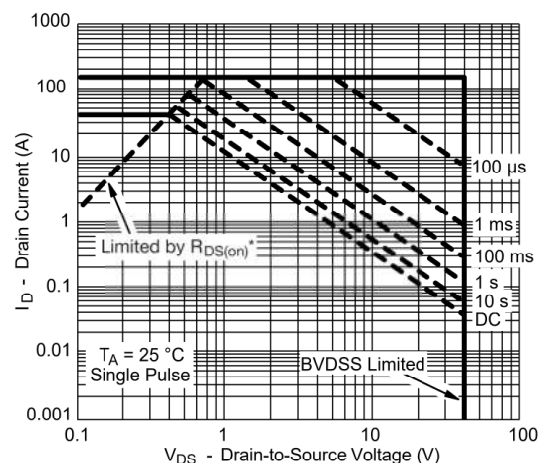
On-Resistance vs. Junction Temperature



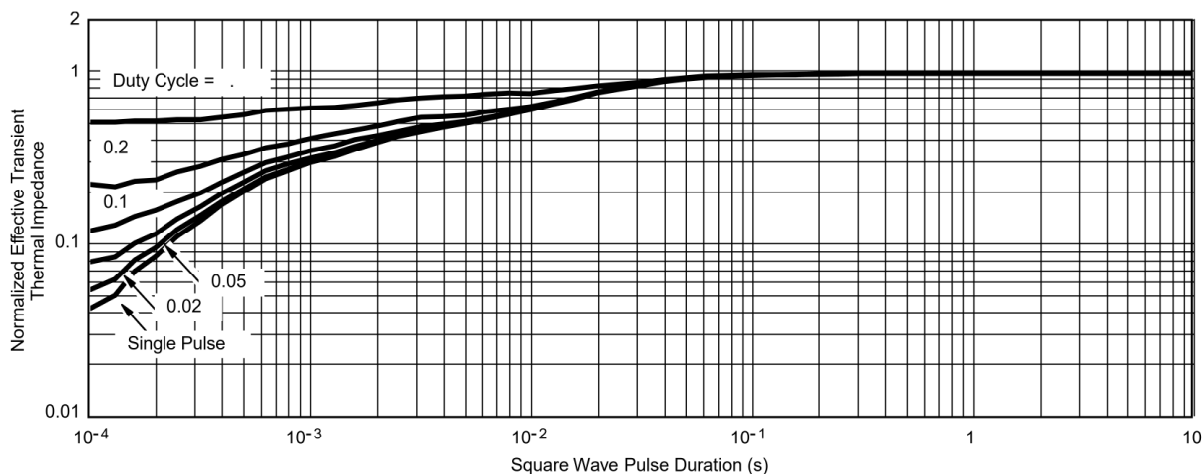
Forward Diode Voltage vs. Temperature



Threshold Voltage

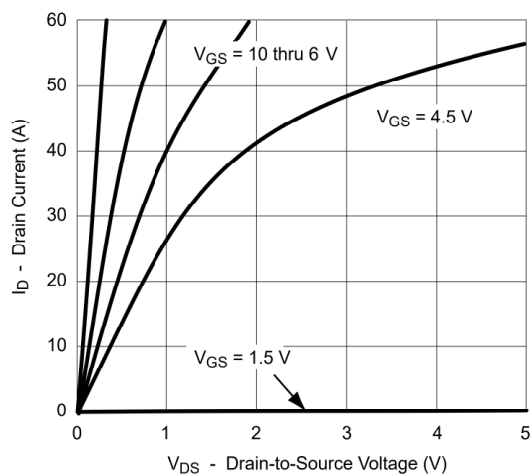


Safe Operating Area, Junction-to-Ambient

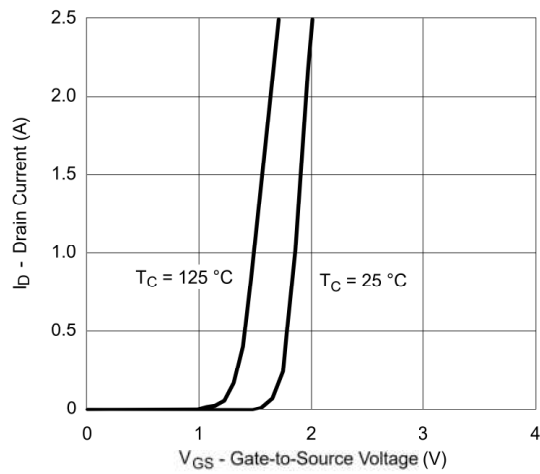


Normalized Thermal Transient Impedance, Junction-to-Case

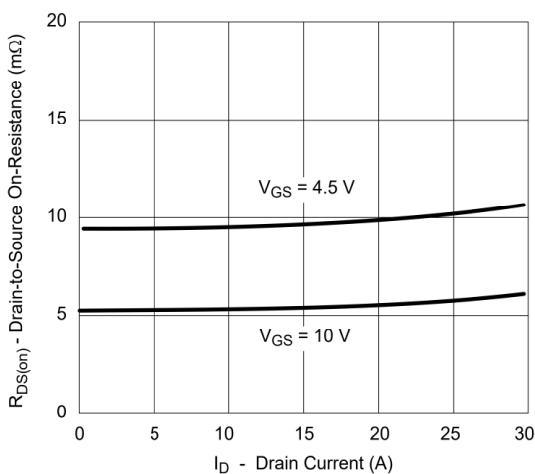
CHANNEL 2 TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



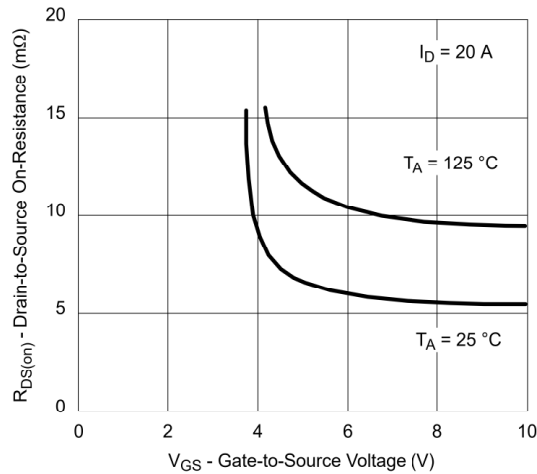
Output Characteristics



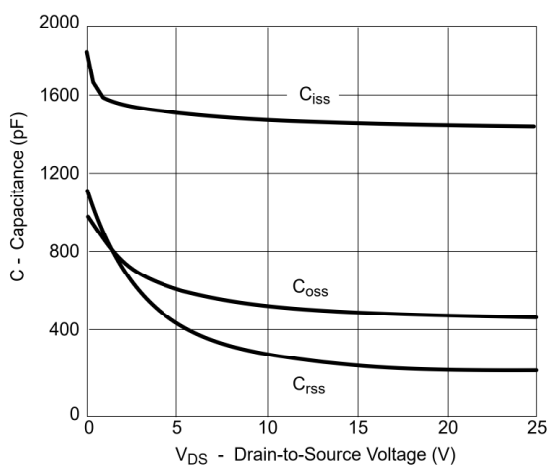
Transfer Characteristics



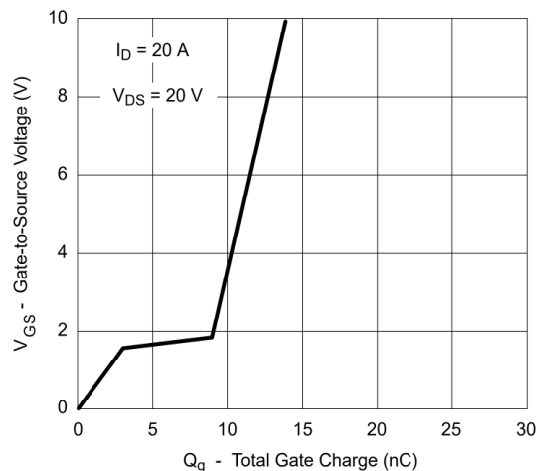
$R_{DS(on)}$ vs. Drain Current



$R_{DS(on)}$ vs. V_{GS} vs. Temperature

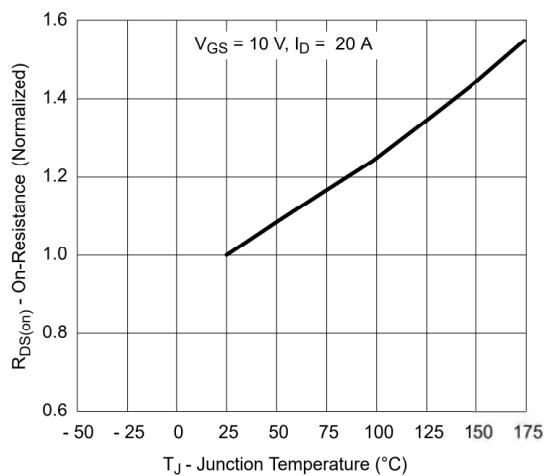


Capacitance

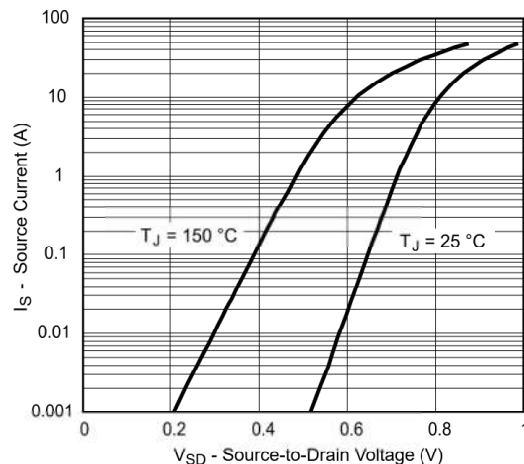


Gate Charge

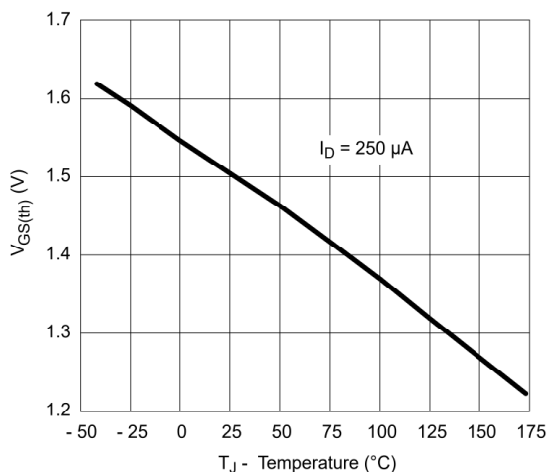
CHANNEL 2 TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



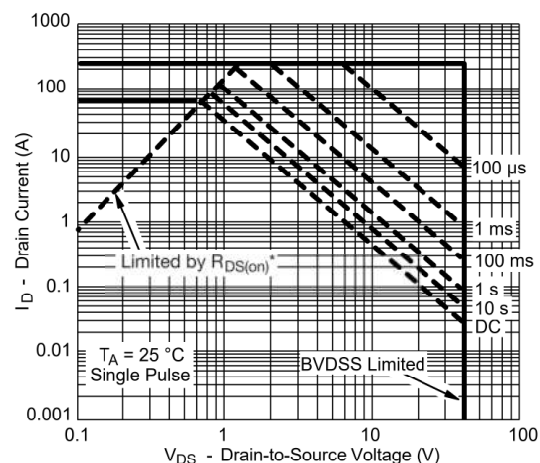
On-Resistance vs. Junction Temperature



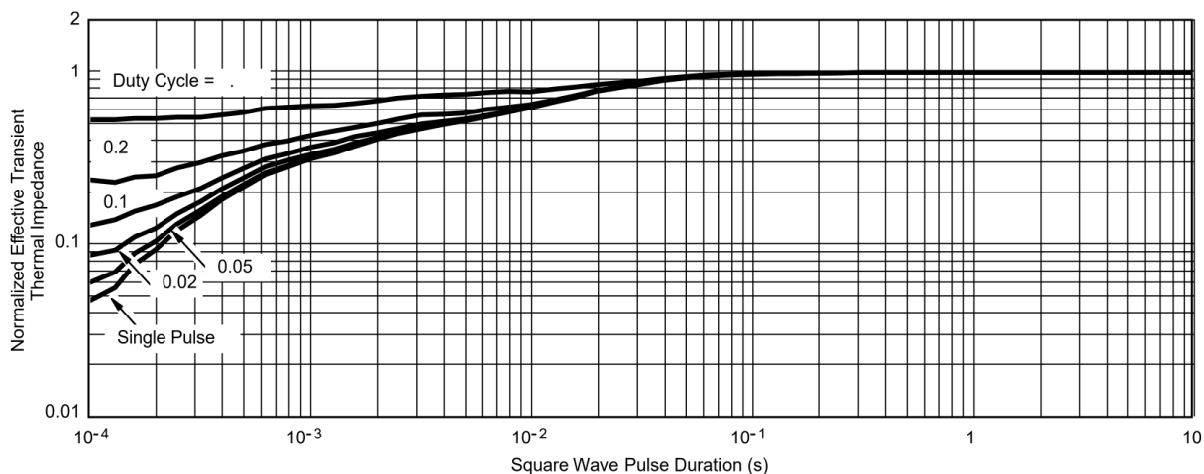
Forward Diode Voltage vs. Temperature



Threshold Voltage



Safe Operating Area, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Case

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